Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/672,035	KANG ET AL.	
Examiner	Art Unit	
Thien F. Tran	2811	

SEARCHED					
Class	Subclass	Date	Examiner		
257	208-209 529-530 665	1/8/2006	Π		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Interference search history printout	1/8/2006	ſΤ		
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